# **Excellent Integrated System Limited**

Stocking Distributor

Click to view price, real time Inventory, Delivery & Lifecycle Information:

Fairchild Semiconductor NDS351AN

For any questions, you can email us directly: <a href="mailto:sales@integrated-circuit.com">sales@integrated-circuit.com</a>

Contact us: sales@integrated-circuit.com Website: www.integrated-circuit.com





June 2003

# NDS351AN

# N-Channel, Logic Level, PowerTrench<sup>o</sup> MOSFET

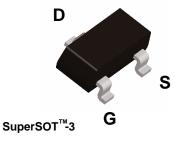
### **General Description**

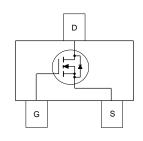
These N-Channel Logic Level MOSFETs are produced Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.

These devices are particularly suited for low voltage applications in notebook computers, portable phones, PCMCIA cards, and other battery powered circuits where fast switching, and low in-line power loss are needed in a very small outline surface mount package.

### **Features**

- $R_{DS(ON)}$  = 160 m $\Omega$  @  $V_{GS}$  = 10 V • 1.4 A, 30 V.  $R_{DS(ON)}$  = 250 m $\Omega$  @  $V_{GS}$  = 4.5 V
- · Ultra-Low gate charge
- Industry standard outline SOT-23 surface mount package using proprietary SuperSOT  $^{\text{TM}}$ -3 design for superior thermal and electrical capabilities
- High performance trench technology for extremely low RDS(ON)





## Absolute Maximum Ratings TA=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V <sub>DSS</sub>	Drain-Source Voltage		30	V
V <sub>GSS</sub>	Gate-Source Voltage		± 20	V
I <sub>D</sub>	Drain Current - Continuous	(Note 1a)	1.4	А
	- Pulsed		10	
P <sub>D</sub>	Power Dissipation for Single Operation	(Note 1a)	0.5	W
		(Note 1b)	0.46	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range		-55 to +150	°C

## **Thermal Characteristics**

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	250	°C/W
R <sub>θJC</sub>	Thermal Resistance, Junction-to-Case	(Note 1)	75	

**Package Marking and Ordering Information** 

Device Marking	Device	Reel Size	Tape width	Quantity
351A	NDS351AN	7"	8mm	3000 units

©2003 Fairchild Semiconductor Corporation



Contact us: sales@integrated-circuit.com Website: www.integrated-circuit.com

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics		I.			I.
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, \qquad I_{D} = 250 \mu\text{A}$	30			V
<u>ΔBV<sub>DSS</sub></u> ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A,Referenced to 25°C		26		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = 24 \text{ V}, \qquad V_{GS} = 0 \text{ V}$			1	μΑ
		$V_{DS} = 24 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55^{\circ}\text{C}$			10	μΑ
$I_{GSS}$	Gate-Body Leakage	$V_{GS} = \pm 20 \text{ V}, \qquad V_{DS} = 0 \text{ V}$			±100	nA
On Char	acteristics (Note 2)					
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 250 \mu A$	0.8	2.1	3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A,Referenced to 25°C		-4		mV/°C
$R_{DS(on)}$	Static Drain–Source On–Resistance	$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$		92 120 114	160 250 214	mΩ
I <sub>D(on)</sub>	On–State Drain Current	$V_{GS} = 4.5V$ , $V_{DS} = 5 V$	3.5			Α
g <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 5 V, I <sub>D</sub> = 1.4 A		4		S
	Characteristics		<u>I</u>	l	I	<u>I</u>
C <sub>iss</sub>	Input Capacitance	$V_{DS} = 15 \text{ V}, \qquad V_{GS} = 0 \text{ V},$		145		pF
Coss	Output Capacitance	f = 1.0 MHz		35		pF
C <sub>rss</sub>	Reverse Transfer Capacitance	7		15		pF
R <sub>G</sub>	Gate Resistance	V <sub>GS</sub> = 15 mV, f = 1.0 MHz		1.6		Ω
Switchin	g Characteristics (Note 2)					
t <sub>d(on)</sub>	Turn-On Delay Time	$V_{DD} = 15 \text{ V}, \qquad I_{D} = 1 \text{ A},$		3	6	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{GS} = 10 \text{ V}, \qquad R_{GEN} = 6 \Omega$		8	16	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	7		16	29	ns
t <sub>f</sub>	Turn-Off Fall Time	7		2	4	ns
Q <sub>g</sub>	Total Gate Charge	$V_{DS} = 15 \text{ V}, \qquad I_{D} = 1.4 \text{ A},$		1.3	1.8	nC
Q <sub>gs</sub>	Gate-Source Charge	$V_{GS} = 4.5 \text{ V}$		0.5		nC
$Q_{gd}$	Gate-Drain Charge			0.5		nC
Drain-S	ource Diode Characteristics	and Maximum Ratings				
Is	Maximum Continuous Drain–Source				0.42	Α
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V},  I_S = 0.42 \text{ A}  \text{(Note 2)}$		0.8	1.2	V
t <sub>rr</sub>	Diode Reverse Recovery Time	$I_F = 1.4 \text{ A}, \qquad d_{iF}/d_t = 100 \text{ A/}\mu\text{s}$		11		nS
Q <sub>rr</sub>	Diode Reverse Recovery Charge	7		4		nC

### Notes

 R<sub>B,JA</sub> is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R<sub>B,JC</sub> is guaranteed by design while R<sub>BCA</sub> is determined by the user's board design.



 a) 250°C/W when mounted on a 0.02 in² pad of 2 oz. copper.



b) 270°C/W when mounted on a minimum pad.

Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width  $\leq$  300  $\mu$ s, Duty Cycle  $\leq$  2.0%





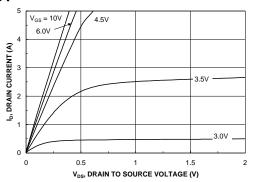


Figure 1. On-Region Characteristics.

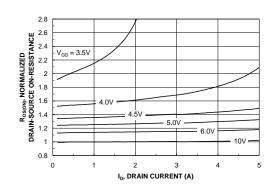


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

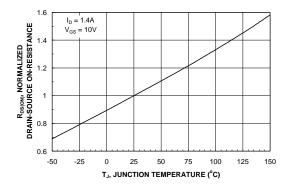


Figure 3. On-Resistance Variation with Temperature.

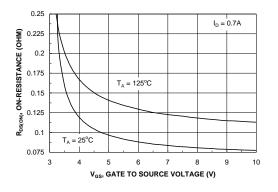


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

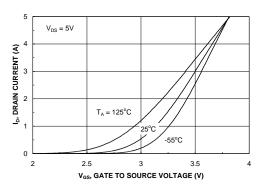


Figure 5. Transfer Characteristics.

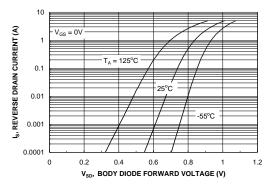
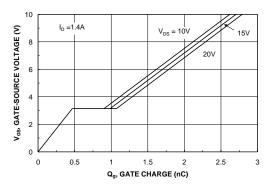


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.



## **Typical Characteristics**



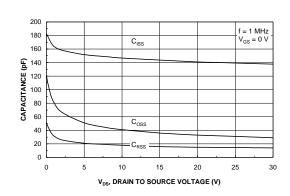


Figure 7. Gate Charge Characteristics.

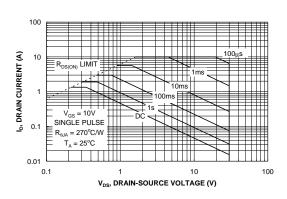


Figure 8. Capacitance Characteristics.

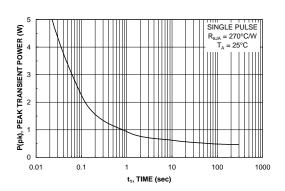


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

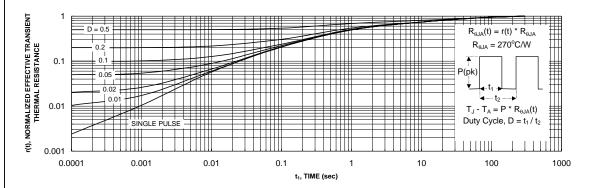


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1b. Transient thermal response will change depending on the circuit board design.



# Distributor of Fairchild Semiconductor: Excellent Integrated System Limited

Datasheet of NDS351AN - MOSFET N-CH 30V 1.4A SSOT3

Contact us: sales@integrated-circuit.com Website: www.integrated-circuit.com

### **TRADEMARKS**

The following are registered and unregistered trademarks Fairchild Semiconductor owns or is authorized to use and is not intended to be an exhaustive list of all such trademarks.

 $ACEx^{TM}$ FACT Quiet Series™ LittleFET™ Power247™ SuperSOT™-6  $Active Array^{\mathsf{TM}}$ MICROCOUPLER™ PowerTrench® SuperSOT™-8 **FAST®**  $Bottomless^{\mathsf{TM}}$  $\mathsf{QFET}^{\mathbb{B}}$ SyncFET™ FASTr™ MicroFET™  $QS^{TM}$ CoolFET™ MicroPak™ TinyLogic<sup>®</sup> FRFET™ GlobalOptoisolator™ MICROWIRE™ CROSSVOLT™ QT Optoelectronics™ TINYOPTO™ Quiet Series™ TruTranslation™ DOME™  $\mathsf{GTO}^{\mathsf{TM}}$  $MSX^{TM}$ EcoSPARK™  $MSXPro^{TM}$ RapidConfigure™ **UHCTM** HiSeC™ RapidConnect™ UltraFET® E<sup>2</sup>CMOS<sup>TM</sup>  $I^2C^{TM}$  $OCX^{TM}$ SILENT SWITCHER®  $VCX^{TM}$ EnSigna™ ImpliedDisconnect<sup>™</sup> OCXPro<sup>™</sup>  $\mathsf{FACT}^\mathsf{TM}$ OPTOLOGIC® ISOPLANAR™ SMART START™ Across the board. Around the world.™ OPTOPLANAR™ SPM™ Stealth™  $PACMAN^{TM}$ The Power Franchise™ РОРТМ SuperSOT™-3 Programmable Active Droop™

#### **DISCLAIMER**

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION OR DESIGN. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS.

#### LIFE SUPPORT POLICY

FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION. As used berein:

1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, or (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in significant injury to the

2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

### PRODUCT STATUS DEFINITIONS

### **Definition of Terms**

Datasheet Identification	Product Status	Definition
Advance Information	Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	This datasheet contains preliminary data, and supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
No Identification Needed	Full Production	This datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
Obsolete	Not In Production	This datasheet contains specifications on a product that has been discontinued by Fairchild semiconductor. The datasheet is printed for reference information only.

Rev. I5